

# 1-Mbit (64 K × 16) Static RAM

### **Features**

- Temperature ranges
  □ Industrial: -40 °C to 85 °C
  □ Automotive-A: -40 °C to 85 °C
- Pin-and function-compatible with CY7C1021CV33
- High speed

  □ t<sub>AA</sub> = 10 ns
- Low active power
  □ I<sub>CC</sub> = 60 mA @ 10 ns
- Low CMOS standby power
  □ I<sub>SB2</sub> = 3 mA
- 2.0 V data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Independent control of upper and lower bits
- Available in Pb-free 44-pin 400-Mil wide molded SOJ, 44-pin TSOP II and 48-ball VFBGA packages

### **Functional Description**

The CY7C1021DV33 is a high-performance CMOS static RAM organized as 65,536 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

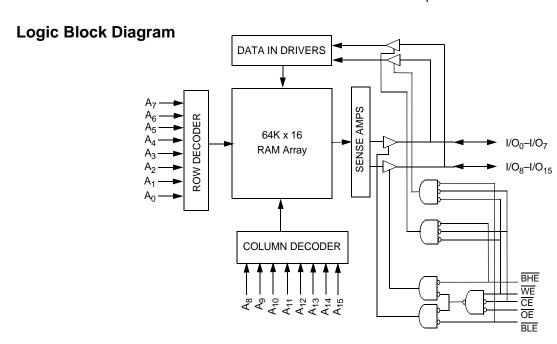
Writing to the device is accomplished by taking Chip Enable  $(\overline{CE})$  and Write Enable  $(\overline{WE})$  inputs LOW. If Byte Low Enable  $(\overline{BLE})$  is LOW, then data from I/O pins  $(I/O_0$  through  $I/O_7)$ , is written into the location specified on the address pins  $(A_0$  through  $A_{15})$ . If Byte High Enable  $(\overline{BHE})$  is LOW, then data from I/O pins  $(I/O_8$  through  $I/O_{15})$  is written into the location specified on the address pins  $(A_0$  through  $A_{15})$ .

Reading from the device is accomplished by taking Chip Enable  $(\overline{\text{CE}})$  and Output Enable  $(\overline{\text{OE}})$  LOW while forcing the Write Enable  $(\overline{\text{WE}})$  HIGH. If Byte Low Enable  $(\overline{\text{BLE}})$  is LOW, then data from the memory location specified by the address pins will appear on I/O<sub>0</sub> to I/O<sub>7</sub>. If Byte High Enable  $(\overline{\text{BHE}})$  is LOW, then data from memory will appear on I/O<sub>8</sub> to I/O<sub>15</sub>. See the truth table at the end of this data sheet for a complete description of Read and Write modes.

The input/output pins (I/O $_0$  through I/O $_{15}$ ) are placed in a high-impedance state when the device is deselected ( $\overline{\text{CE HIGH}}$ ), the outputs are disabled ( $\overline{\text{OE HIGH}}$ ), the BHE and BLE are disabled ( $\overline{\text{BHE}}$ , BLE HIGH), or during a Write operation ( $\overline{\text{CE LOW}}$ , and  $\overline{\text{WE LOW}}$ ).

The CY7C1021DV33 is available in Pb-free 44-pin 400-Mil wide Molded SOJ, 44-pin TSOP II and 48-ball VFBGA packages.

For a complete list of related resources, click here.





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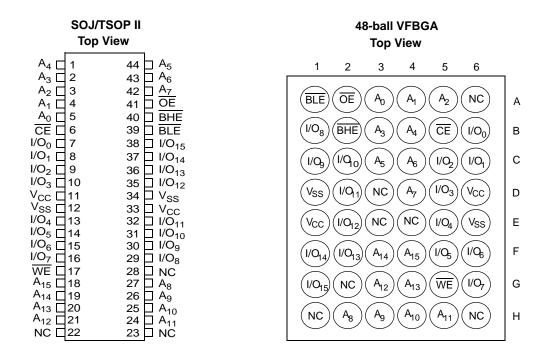


### **Selection Guide**

| Description                  | -10 (Industrial /<br>Automotive-A) | Unit |
|------------------------------|------------------------------------|------|
| Maximum access time          | 10                                 | ns   |
| Maximum operating current    | 60                                 | mA   |
| Maximum CMOS standby current | 3                                  | mA   |

## **Pin Configurations**

SOJ, TSOP II and VFBGA pinouts are as follows. [1]



### Note

NC pins are not connected on the die.



## **Maximum Ratings**

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

| Current into outputs (LOW)     | 20 mA    |
|--------------------------------|----------|
| Static discharge voltage       |          |
| (per MIL-STD-883, method 3015) | > 2001 V |
| Latch-up current               | > 200 mA |

## **Operating Range**

|   | Range        | Ambient<br>Temperature | v <sub>cc</sub> | Speed |
|---|--------------|------------------------|-----------------|-------|
|   | Industrial   | –40 °C to +85 °C       | $3.3~V\pm0.3~V$ | 10 ns |
| Ī | Automotive-A | -40 °C to +85 °C       |                 | 10 ns |

### **Electrical Characteristics**

Over the Operating Range

### **DC Electrical Characteristics**

Over the Operating Range

| Parameter        | Description                                      | Test Conditions   | Test Conditions            |      |                | Unit |
|------------------|--|---|----------------------------|------|----------------|------|
|                  | ·  |   |                            | Min  | Max            |      |
| V <sub>OH</sub>  | Output HIGH voltage                              | $V_{CC}$ = Min, $I_{OH}$ = -4.0 mA  |                            | 2.4  | -              | V    |
| $V_{OL}$         | Output LOW voltage                               | $V_{CC}$ = Min, $I_{OL}$ = 8.0 mA   |                            | _    | 0.4            | V    |
| V <sub>IH</sub>  | Input HIGH voltage                               |   |                            | 2.0  | $V_{CC} + 0.3$ | V    |
| V <sub>IL</sub>  | Input LOW voltage [2]                            |   |                            | -0.3 | 0.8            | V    |
| I <sub>IX</sub>  | Input leakage current                            | $GND \le V_I \le V_{CC}$  | $GND \le V_{I} \le V_{CC}$ |      |                | μΑ   |
| I <sub>OZ</sub>  | Output leakage current                           | $GND \le V_I \le V_{CC}$ , Output Disabled  |                            | -1   | +1             | μΑ   |
| I <sub>CC</sub>  | V <sub>CC</sub> operating supply current         | V <sub>CC</sub> = Max, I <sub>OUT</sub> = 0 mA,   | 100 MHz                    | _    | 60             | mA   |
|                  |  | $f = f_{MAX} = 1/t_{RC}$  | 83 MHz                     | _    | 55             | mA   |
|                  |  |   | 66 MHz                     | _    | 45             | mA   |
|                  |  |   | 40 MHz                     | _    | 30             | mA   |
| I <sub>SB1</sub> | Automatic CE Power-Down<br>Current – TTL Inputs  | $\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{ f} = \text{f}_{\text{MAX}} \end{aligned}$ |                            | _    | 10             | mA   |
| I <sub>SB2</sub> | Automatic CE Power-Down<br>Current – CMOS Inputs | $\begin{array}{c} \text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V or V}_{\text{IN}} \leq 0.3 \text{ V}, \text{f} = \\ \end{array}$       | : 0                        | -    | 3              | mA   |

Note

Document Number: 38-05460 Rev. \*H

<sup>2.</sup>  $V_{IL(min)} = -2.0 \text{ V}$  and  $V_{IH(max)} = V_{CC} + 1 \text{ V}$  for pulse durations of less than 5 ns.



## Capacitance

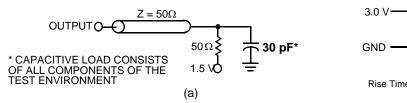
| Parameter [3]    | Description        | Test Conditions  | Max | Unit |
|------------------|--------------------|--|-----|------|
| C <sub>IN</sub>  | Input capacitance  | $T_A = 25 ^{\circ}\text{C}$ , $f = 1 \text{MHz}$ , $V_{CC} = 3.3 \text{V}$ | 8   | pF   |
| C <sub>OUT</sub> | Output capacitance |  | 8   | pF   |

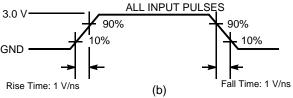
### **Thermal Resistance**

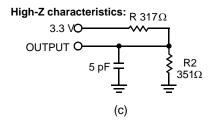
| Parameter [3]     | Description                           | Test Conditions   | SOJ   | TSOP II | VFBGA | Unit |
|-------------------|---------------------------------------|---|-------|---------|-------|------|
| $\Theta_{JA}$     |                                       | Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit |       | 53.91   | 36    | °C/W |
| $\Theta_{\sf JC}$ | Thermal resistance (junction to case) | board   | 36.75 | 21.24   | 9     | °C/W |

## **AC Test Loads and Waveforms**

Figure 1. AC Test Loads and Waveforms [4]







- Notes
  3. Tested initially and after any design or process changes that may affect these parameters.
  4. AC characteristics (except High Z) are tested using the load conditions shown in Figure 1 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 1 (c).



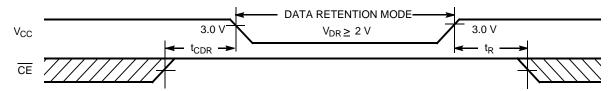
## **Data Retention Characteristics**

Over the Operating Range

| Parameter                       | Description                          | Conditions  | Min             | Max | Unit |
|---------------------------------|--------------------------------------|---|-----------------|-----|------|
| $V_{DR}$                        | V <sub>CC</sub> for data retention   |   | 2               | _   | V    |
| I <sub>CCDR</sub>               | Data retention current               | $ \begin{vmatrix} V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V}, \\ V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V} \end{vmatrix}                                  $ | rial –          | 3   | mA   |
| t <sub>CDR</sub> <sup>[5]</sup> | Chip deselect to data retention time |   | 0               | _   | ns   |
| t <sub>R</sub> <sup>[6]</sup>   | Operation recovery time              |   | t <sub>RC</sub> | _   | ns   |

### **Data Retention Waveform**

Figure 2. Data Retention Waveform



 <sup>5.</sup> Tested initially and after any design or process changes that may affect these parameters.
 6. Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min)</sub> ≥ 50 μs or stable at V<sub>CC(min)</sub> ≥ 50 μs.



## **Switching Characteristics**

Over the Operating Range

| Parameter [7]                     | Description                                   | -10 (Ind<br>Autom | -10 (Industrial /<br>Automotive-A) |    |
|-----------------------------------|---|-------------------|------------------------------------|----|
|                                   | ·   | Min               | Max                                |    |
| Read Cycle                        |   |                   |                                    | •  |
| t <sub>power</sub> <sup>[8]</sup> | V <sub>CC</sub> (typical) to the first access | 100               | _                                  | μS |
| t <sub>RC</sub>                   | Read cycle time                               | 10                | _                                  | ns |
| t <sub>AA</sub>                   | Address to data valid                         | _                 | 10                                 | ns |
| t <sub>OHA</sub>                  | Data hold from address change                 | 3                 | _                                  | ns |
| t <sub>ACE</sub>                  | CE LOW to data valid                          | _                 | 10                                 | ns |
| t <sub>DOE</sub>                  | OE LOW to data valid                          | _                 | 5                                  | ns |
| t <sub>LZOE</sub>                 | OE LOW to low Z [9]                           | 0                 | _                                  | ns |
| t <sub>HZOE</sub>                 | OE HIGH to high Z [9, 10]                     | _                 | 5                                  | ns |
| t <sub>LZCE</sub>                 | CE LOW to low Z [9]                           | 3                 | _                                  | ns |
| t <sub>HZCE</sub>                 | CE HIGH to high Z [9, 10]                     | _                 | 5                                  | ns |
| t <sub>PU</sub> <sup>[11]</sup>   | CE LOW to power-up                            | 0                 | _                                  | ns |
| t <sub>PD</sub> <sup>[11]</sup>   | CE HIGH to power-down                         | _                 | 10                                 | ns |
| t <sub>DBE</sub>                  | Byte Enable to data valid                     | _                 | 5                                  | ns |
| t <sub>LZBE</sub>                 | Byte Enable to low Z                          | 0                 | _                                  | ns |
| t <sub>HZBE</sub>                 | Byte Disable to high Z                        | _                 | 6                                  | ns |
| Write Cycle [12                   | , 13]   |                   |                                    | •  |
| t <sub>WC</sub>                   | Write cycle time                              | 10                | _                                  | ns |
| t <sub>SCE</sub>                  | CE LOW to write end                           | 8                 | _                                  | ns |
| t <sub>AW</sub>                   | Address set-up to write end                   | 8                 | _                                  | ns |
| t <sub>HA</sub>                   | Address hold from write end                   | 0                 | _                                  | ns |
| t <sub>SA</sub>                   | Address set-up to write start                 | 0                 | _                                  | ns |
| t <sub>PWE</sub>                  | WE pulse width                                | 7                 | _                                  | ns |
| t <sub>SD</sub>                   | Data set-up to write end                      | 5                 | -                                  | ns |
| t <sub>HD</sub>                   | Data hold from write end                      | 0                 | _                                  | ns |
| t <sub>LZWE</sub>                 | WE HIGH to low Z <sup>[9]</sup>               | 3                 | _                                  | ns |
| t <sub>HZWE</sub>                 | WE LOW to high Z <sup>[9, 10]</sup>           | _                 | 5                                  | ns |
| t <sub>BW</sub>                   | Byte enable to end of write                   | 7                 | _                                  | ns |

- 7. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.

  8. t<sub>POWER</sub> gives the minimum amount of time that the power supply should be at typical V<sub>CC</sub> values until the first memory access can be performed.

  9. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.

  10. t<sub>HZCE</sub>, t<sub>HZE</sub>, t<sub>HZCE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in (c) of Figure 1 on page 5. Transition is measured when the outputs enter a high impedance state.

  11. This parameter is guaranteed by design and is not tested.

  12. The internal Write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE/BLE LOW. CE, WE and BHE/BLE must be LOW to initiate a Write and the transition of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
- 13. The minimum write pulse width for Write Cycle No. 3 (WE Controlled, OE LOW) should be equal to the sum of t<sub>SD</sub> and t<sub>HZWE</sub>.



## **Switching Waveforms**

Figure 3. Read Cycle No. 1 (Address Transition Controlled) [14, 15]

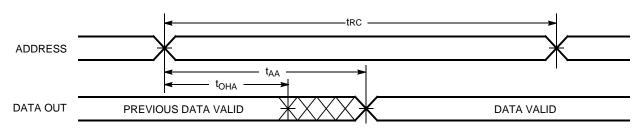
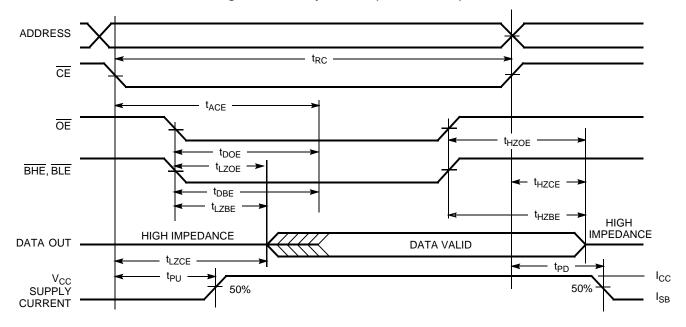


Figure 4. Read Cycle No. 2 (OE Controlled) [15, 16]



<sup>14. &</sup>lt;u>Dev</u>ice is continuously selected. <u>OE</u>, <u>CE</u>, <u>BHE</u> and/or <u>BLE</u> = V<sub>IL</sub>. 15. WE is HIGH for Read cycle.

<sup>16.</sup> Address valid prior to or coincident with  $\overline{\text{CE}}$  transition LOW.



## Switching Waveforms (continued)

Figure 5. Write Cycle No. 1 (CE Controlled) [17, 18]

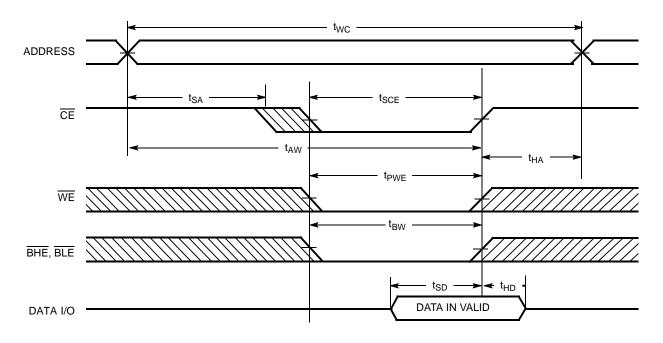
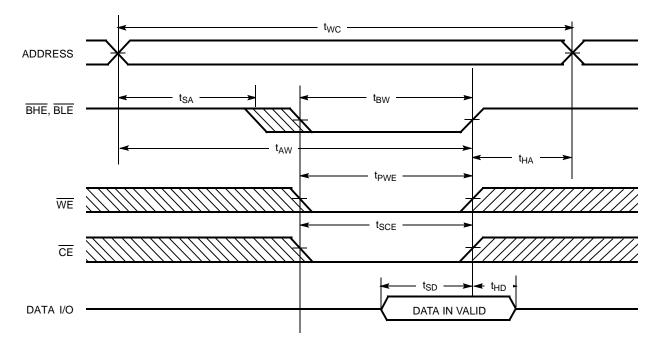


Figure 6. Write Cycle No. 2 (BLE or BHE Controlled)



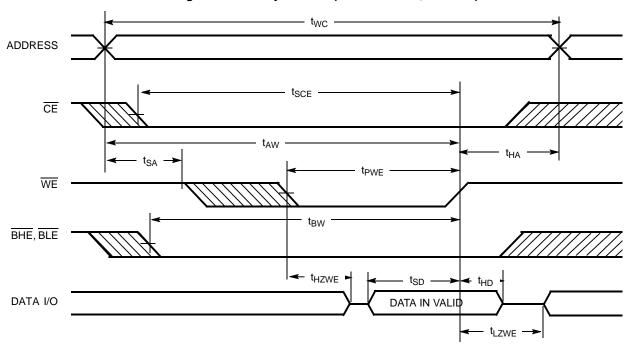
<sup>17.</sup> Data I/O is high impedance if  $\overline{OE}$  or  $\overline{BHE}$  and/or  $\overline{BLE}$  =  $V_{IH}$ .

18. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  going HIGH, the output remains in a high-impedance state.



## Switching Waveforms (continued)

Figure 7. Write Cycle No. 3 (WE Controlled, OE LOW) [19]



### Note

<sup>19.</sup> The minimum write pulse width should be equal to the sum of  $t_{\text{SD}}$  and  $t_{\text{HZWE}}$ .



## **Truth Table**

| CE | ŌE | WE | BLE | BHE | I/O <sub>0</sub> –I/O <sub>7</sub> | I/O <sub>8</sub> –I/O <sub>15</sub> | Mode                       | Power                      |
|----|----|----|-----|-----|------------------------------------|-------------------------------------|----------------------------|----------------------------|
| Н  | Х  | Х  | Х   | X   | High-Z                             | High-Z                              | Power-down                 | Standby (I <sub>SB</sub> ) |
| L  | L  | Н  | L   | L   | Data Out                           | Data Out                            | Read – All bits            | Active (I <sub>CC</sub> )  |
|    |    |    | L   | Н   | Data Out                           | High-Z                              | Read – Lower bits only     | Active (I <sub>CC</sub> )  |
|    |    |    | Н   | L   | High-Z                             | Data Out                            | Read – Upper bits only     | Active (I <sub>CC</sub> )  |
| L  | Х  | L  | L   | L   | Data In                            | Data In                             | Write – All bits           | Active (I <sub>CC</sub> )  |
|    |    |    | L   | Н   | Data In                            | High-Z                              | Write – Lower bits only    | Active (I <sub>CC</sub> )  |
|    |    |    | Н   | L   | High-Z                             | Data In                             | Write – Upper bits only    | Active (I <sub>CC</sub> )  |
| L  | Н  | Н  | Х   | Х   | High-Z                             | High-Z                              | Selected, outputs disabled | Active (I <sub>CC</sub> )  |
| L  | Х  | Х  | Н   | Н   | High-Z                             | High-Z                              | Selected, outputs disabled | Active (I <sub>CC</sub> )  |

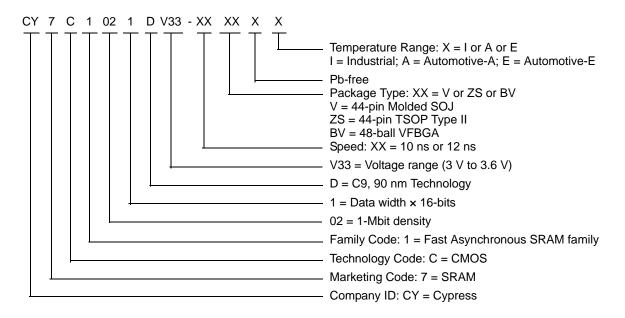


## **Ordering Information**

| Speed (ns) | Ordering Code       | Package<br>Diagram | Package Type                          | Operating<br>Range |
|------------|---------------------|--------------------|---------------------------------------|--------------------|
| 10         | CY7C1021DV33-10VXI  | 51-85082           | 44-pin (400-Mil) Molded SOJ (Pb-free) | Industrial         |
|            | CY7C1021DV33-10ZSXI | 51-85087           | 44-pin TSOP Type II (Pb-free)         |                    |
|            | CY7C1021DV33-10BVXI | 51-85150           | 48-ball VFBGA (Pb-free)               |                    |
| 10         | CY7C1021DV33-10ZSXA | 51-85087           | 44-pin TSOP Type II (Pb-free)         | Automotive-A       |

Please contact your local Cypress sales representative for availability of these parts.

### **Ordering Code Definitions**





### **Package Diagrams**

Figure 8. 44-pin SOJ (400 Mils) V44.4 Package Outline, 51-85082

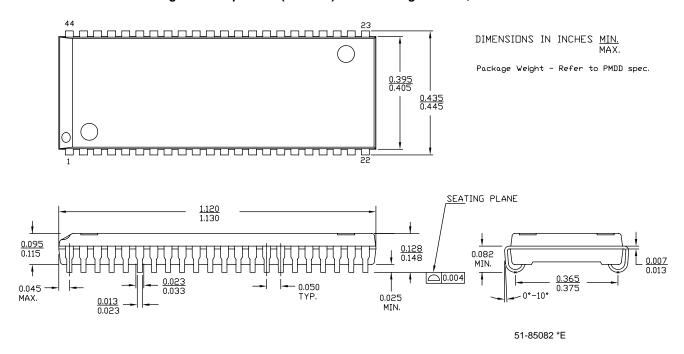
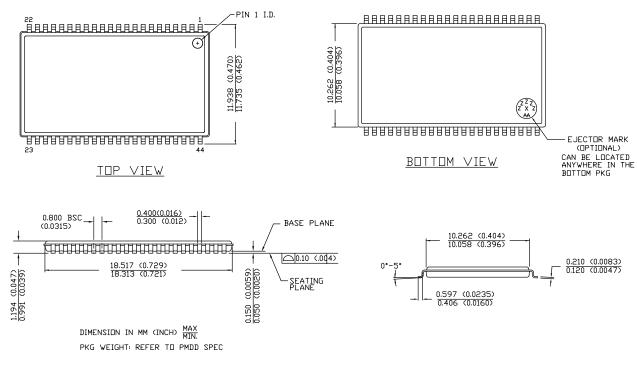


Figure 9. 44-pin TSOP Z44-II Package Outline, 51-85087

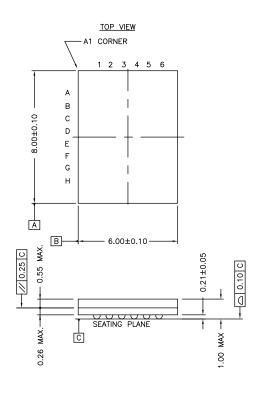


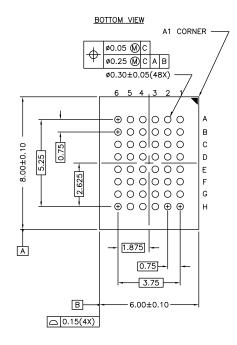
51-85087 \*E



## Package Diagrams (continued)

Figure 10. 48-ball VFBGA (6 x 8 x 1.0 mm) BV48/BZ48 Package Outline, 51-85150





NOTE:
PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD)
posted on the Cypress web.

51-85150 \*H



## Acronyms

| Acronym | Description                             |  |  |  |  |  |
|---------|---|--|--|--|--|--|
| BHE     | Byte High Enable                        |  |  |  |  |  |
| BLE     | Byte Low Enable                         |  |  |  |  |  |
| CMOS    | Complementary Metal Oxide Semiconductor |  |  |  |  |  |
| CE      | Chip Enable                             |  |  |  |  |  |
| I/O     | Input/Output                            |  |  |  |  |  |
| OE      | Output Enable                           |  |  |  |  |  |
| SOJ     | Small-Outline J-leaded                  |  |  |  |  |  |
| SRAM    | Static Random Access Memory             |  |  |  |  |  |
| TSOP    | Thin Small-Outline Package              |  |  |  |  |  |
| TTL     | Transistor-Transistor Logic             |  |  |  |  |  |
| VFBGA   | Very Fine-Pitch Ball Grid Array         |  |  |  |  |  |
| WE      | Write Enable                            |  |  |  |  |  |

## **Document Conventions**

### **Units of Measure**

| Symbol | Unit of Measure |  |  |  |  |
|--------|-----------------|--|--|--|--|
| °C     | degree Celsius  |  |  |  |  |
| MHz    | megahertz       |  |  |  |  |
| μΑ     | microampere     |  |  |  |  |
| μs     | microsecond     |  |  |  |  |
| mA     | milliampere     |  |  |  |  |
| ns     | nanosecond      |  |  |  |  |
| %      | percent         |  |  |  |  |
| pF     | picofarad       |  |  |  |  |
| V      | volt            |  |  |  |  |
| W      | watt            |  |  |  |  |



## **Document History Page**

| ocument<br>ocument | cument Title: CY7C1021DV33, 1-Mbit (64 K × 16) Static RAM<br>cument Number: 38-05460 |            |                    |   |  |  |  |  |
|--------------------|--|------------|--------------------|---|--|--|--|--|
| Rev.               | ECN No.  | Issue Date | Orig. of<br>Change | Description of Change   |  |  |  |  |
| **                 | 201560   | See ECN    | SWI                | Advance Information data sheet for C9 IPP.  |  |  |  |  |
| *A                 | 233693   | See ECN    | RKF                | Updated Electrical Characteristics (modified as per Eros (Spec # 01-02165) Updated Ordering Information (included Pb-free offering).  |  |  |  |  |
| *B                 | 263769   | See ECN    | RKF                | Updated Functional Description (Changed I/O <sub>1</sub> –I/O <sub>16</sub> to I/O <sub>0</sub> –I/O <sub>15</sub> ). Updated Pin Configurations (Changed I/O <sub>1</sub> –I/O <sub>16</sub> to I/O <sub>0</sub> –I/O <sub>15</sub> ). Added Data Retention Characteristics and Data Retention Waveform. Updated Switching Characteristics (Added T <sub>power</sub> parameter and its details) Updated Ordering Information (Added shade, no change in part numbers).   |  |  |  |  |
| *C                 | 307601   | See ECN    | RKF                | Updated Selection Guide (Reduced Speed bins to -8 and -10 ns (Removed -1 and -15 speed bins related information)). Updated Electrical Characteristics (Reduced Speed bins to -8 and -10 ns (Removed -12 and -15 speed bins related information)). Updated Switching Characteristics (Reduced Speed bins to -8 and -10 ns (Removed -12 and -15 speed bins related information)). Updated Ordering Information (Updated part numbers).  |  |  |  |  |
| *D                 | 520652   | See ECN    | VKN                | Changed status from Preliminary to Final.  Updated Features (Removed Commercial Operating range related information and included Automotive-A, Automotive-E Operating range related information).  Updated Selection Guide (Removed -8 speed bin related information and included -12 speed bin related information).  Updated Operating Range (Removed Commercial Operating range related information and included Automotive-A, Automotive-E Operating range related information).  Updated Electrical Characteristics (Updated DC Electrical Characteristics (Removed -8 speed bin related information and included -12 speed bin related information, removed Commercial Operating range related information and included Automotive-A, Automotive-E Operating range related information), Updated Note 2 (Changed V <sub>IH(max)</sub> from V <sub>CC</sub> + 2 V to V <sub>CC</sub> + 1 V), added I <sub>C</sub> parameter values for the frequencies 83 MHz, 66 MHz and 40 MHz).  Updated Thermal Resistance (Replaced TBD with values for all packages). Updated Switching Characteristics (Removed -8 speed bin related information and included -12 speed bin related information, removed Commercial Operating range related information and included Automotive-A, Automotive-Operating range related information).  Updated Data Retention Characteristics (Removed Commercial Operating range related information) and included Automotive-A, Automotive-E Operating range related information and included Automotive-A, Automotive-E Operating range related information).  Updated Ordering Information) (Updated part numbers). |  |  |  |  |
| *E                 | 2898399  | 03/24/2010 | AJU                | Updated Package Diagrams.   |  |  |  |  |
| *F                 | 3109897  | 12/14/2010 | AJU                | Added Ordering Code Definitions. Updated Package Diagrams.  |  |  |  |  |



## **Document History Page** (continued)

| Rev. | ECN No. | Issue Date | Orig. of<br>Change | Description of Change  |
|------|---------|------------|--------------------|--|
| *G   | 3421856 | 10/25/2011 | TAVA               | Updated Features (Removed Automotive-E Operating range related information).  Updated Selection Guide (Removed Automotive-E Operating range related information, removed -12 speed bin related information).  Updated Operating Range (Removed Automotive-E Operating range related information, removed -12 speed bin related information).  Updated Electrical Characteristics (Updated DC Electrical Characteristics (Removed Automotive-E Operating range related information, removed -12 speed bin related information)).  Updated Switching Characteristics (Removed Automotive-E Operating range related information, removed -12 speed bin related information).  Updated Data Retention Characteristics (Removed Automotive-E Operating range related information).  Updated Data Retention Characteristics (Removed Automotive-E Operating range related information).  Updated Switching Waveforms.  Updated Ordering Information (Updated part numbers).  Updated Package Diagrams.  Updated to new template. |
| *H   | 4578364 | 11/24/2014 | MEMJ               | Updated Functional Description: Added "For a complete list of related resources, click here." at the end.  Updated Switching Characteristics: Added Note 13 and referred the same note in "Write Cycle".  Updated Switching Waveforms: Added Note 19 and referred the same note in Figure 7.  Updated Ordering Information (Removed shade, no change in part numbers).  Updated Package Diagrams: spec 51-85082 – Changed revision from *D to *E. spec 51-85087 – Changed revision from *D to *E. spec 51-85150 – Changed revision from *G to *H.  Added Acronyms and Units of Measure.  Updated to new template.  Completing Sunset Review.   |



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